

Silicon P-N-P Transistors

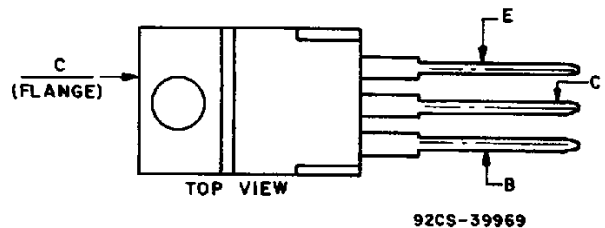
Complementary to the D44VH Series

Features:

- Fast Switching $t_s \leq 500$ ns resistive
 $t_f \leq 100$ ns
- Low $V_{CE(sat)} \leq 1.0V$ @ $I_C = 8A$

The D45VH-series of silicon p-n-p power transistors are especially designed for use in switching circuits such as switching regulators, high-frequency inverters/converters, and other applications where very fast switching times and low-saturation voltages are necessary. These devices are tested for parameters that relate directly to the design of high-power switching circuits. Switching times, saturation voltages, and leakage currents are specified at 100°C to provide information necessary for worst-case design.

TERMINAL DESIGNATIONS



JEDEC TO-220AB

MAXIMUM RATINGS ($T_A = 25^\circ C$) (unless otherwise specified)

RATING	SYMBOL	D45VH1	D45VH4	D45VH7	D45VH10	UNITS
Collector-Emitter Voltage	$V_{CEO(sus)}$	-30	-45	-60	-80	Volts
Collector-Emitter Voltage	V_{CEX}	-40	-55	-70	-90	Volts
Collector-Emitter Voltage	V_{CEV}	-50	-70	-80	-100	Volts
Emitter Base Voltage	V_{EBO}	-7	-7	-7	-7	Volts
Collector Current — Continuous	I_C	-15	-15	-15	-15	A
Peak ⁽¹⁾	I_{CM}	-20	-20	-20	-20	
Base Current — Continuous	I_B	-5	-5	-5	-5	A
Peak ⁽¹⁾	I_{BM}	-10	-10	-10	-10	
Total Power Dissipation @ $T_c = 25^\circ C$	P_D	83	83	83	83	Watts
@ $T_c = 100^\circ C$		33	33	33	33	
Derate above 25°C		0.67	0.67	0.67	0.67	W/°C
Operating and Storage Junction Temperature Range	T_J, T_{STG}	-55 to +150	-55 to +150	-55 to +150	-55 to +150	°C

THERMAL CHARACTERISTICS

Thermal Resistance, Junction to Case	$R_{\theta JC}$	1.5	1.5	1.5	1.5	°C/W
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	75	75	75	75	°C/W
Maximum Lead Temperature for Soldering Purpose: 1/8" from Case for 5 Seconds	T_L	235	235	235	235	°C

(1) Pulse measurement condition $PW \leq 6.0$ ms, see Figure 14.

CHARACTERISTICS	SYMBOL	MIN	MAX	UNIT
OFF CHARACTERISTICS⁽¹⁾				
Collector-Emitter Sustaining Voltage ⁽¹⁾ ($I_C = -100\text{mA}$, $I_B = 0$) D45VH1 D45VH4 D45VH7 D45VH10	$V_{CEO(sus)}$	-30 -45 -60 -80	— — — —	V
Collector-Emitter Voltage ⁽²⁾ ($I_C = -10\text{A}$, $V_{CLAMP} = \text{Rated } V_{CEX}$, $T_C = 100^\circ\text{C}$) D45VH1 D45VH4 D45VH7 D45VH10	V_{CEX}	-40 -55 -70 -90	— — — —	V
Collector Cutoff Current ($V_{CEV} = \text{Rated Value}$, $V_{BE(off)} = 4.0\text{V}$) ($V_{CEV} = \text{Rated Value}$, $V_{BE(off)} = 4.0\text{V}$, $T_C = 100^\circ\text{C}$)	I_{CEV}	— —	-10 -100	μA
Collector Cutoff Current ($V_{CE} = \text{Rated } V_{CEV}$, $R_{BE} = 50\ \Omega$, $T_C = 100^\circ\text{C}$)	I_{CER}	—	-100	μA
Emitter Cutoff Current ($V_{EB} = -7\text{V}$, $I_C = 0$)	I_{EBO}	—	-10	μA

SECOND BREAKDOWN

Second Breakdown with Base Forward Biased	FBSOA	SEE FIGURE 7
Second Breakdown with Base Reverse Biased	RBSOA	SEE FIGURE 8

ON CHARACTERISTICS⁽¹⁾

DC Current Gain ($I_C = -2\text{A}$, $V_{CE} = -1\text{V}$) ($I_C = -4\text{A}$, $V_{CE} = -1\text{V}$)	h_{FE}	35 20	— —	—
Collector-Emitter Saturation Voltage ($I_C = -8\text{A}$, $I_B = -0.8\text{A}$) ($I_C = -8\text{A}$, $I_B = -0.8\text{A}$, $T_C = 100^\circ\text{C}$) ($I_C = -15\text{A}$, $I_B = -3.0\text{A}$, $T_C = 100^\circ\text{C}$)	$V_{CE(sat)}$	— — —	-1.0 -1.1 -1.5	V
Base-Emitter Saturation Voltage ($I_C = -8\text{A}$, $I_B = -0.8\text{A}$) ($I_C = -8\text{A}$, $I_B = -0.8\text{A}$, $T_C = 100^\circ\text{C}$)	$V_{BE(sat)}$	— —	-1.4 -1.4	V

DYNAMIC CHARACTERISTICS

Typical

Current-Gain — Bandwidth Product ($I_C = -0.1\text{A}$, $V_{CE} = -10\text{V}$, $f_{test} = 1\text{MHz}$)	f_T	50		MHz
Output Capacitance ($V_{CB} = -10\text{V}$, $I_E = 0$, $f_{test} = 1\text{MHz}$)	C_{OB}	275		pF

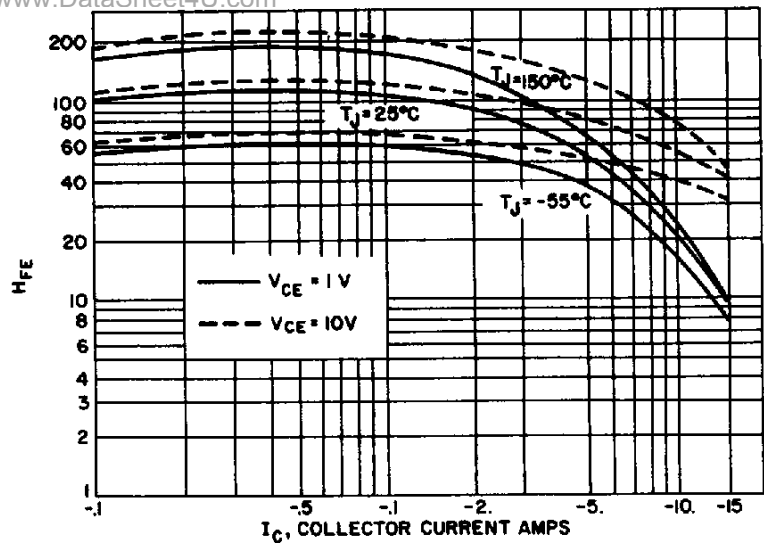
SWITCHING CHARACTERISTICS

Maximum

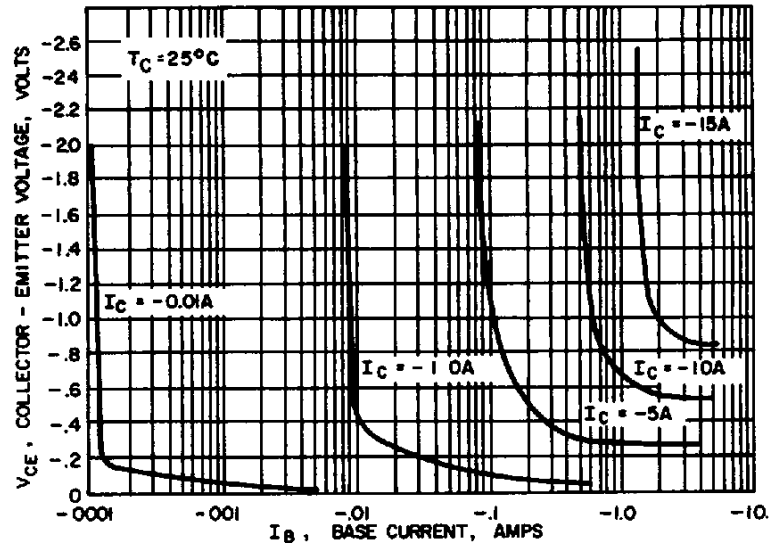
Resistive Load (See Figure 16 for Test Circuit)		T_C	25°C	100°C	
Delay Time	$V_{CC} = -20\text{V}$, $I_C = -8\text{A}$ $I_{B1} = I_{B2} = 0.8\text{A}$ $t_p = 25\ \mu\text{sec}$	t_d	50	—	nsec
Rise Time		t_r	250	—	nsec
Storage Time		t_s	500	—	nsec
Fall Time		t_f	100	—	nsec
Inductive Load, Clamped (See Figure 15 for Test Circuit)					
Storage Time	$V_{CC} = -20\text{V}$, $I_C = -8\text{A}$ $V_{CLAMP} = \text{Rated } V_{CEX}$ $I_{B1} = -0.8\text{A}$, $V_{BE(off)} = 5\text{V}$	t_s	500	600	nsec
Fall Time		t_f	300	400	nsec
Typical					
Storage Time	L = 200 μh	t_s	200	320	nsec
Fall Time		t_f	160	180	nsec

(1) Pulse Duration = 300 μsec , Duty Factor $\leq 2\%$.

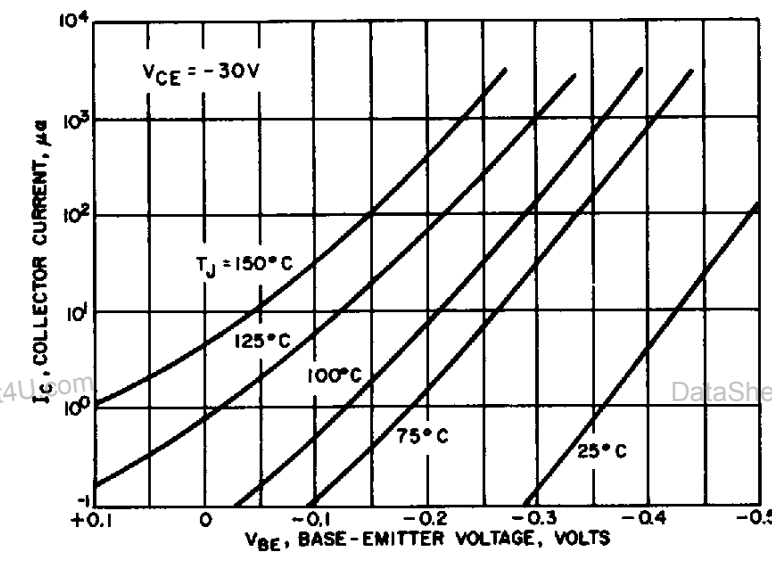
(2) See Figure 15 for Test Circuit.



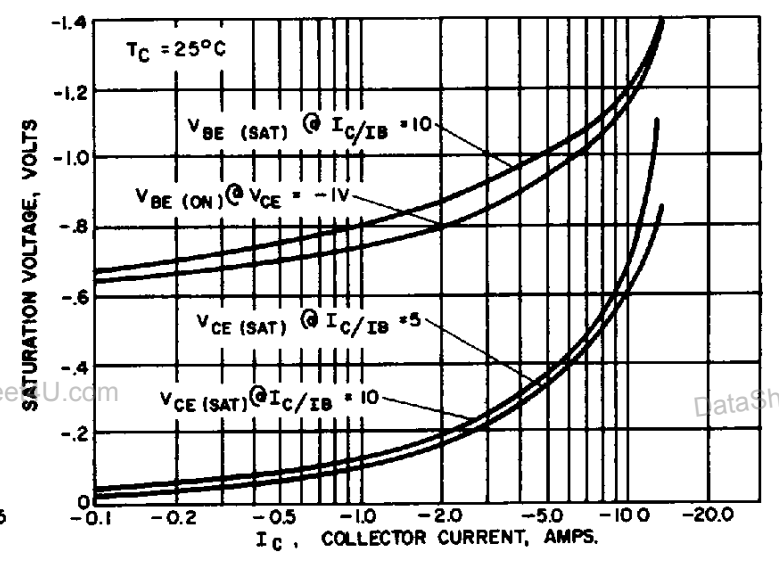
1. DC CURRENT GAIN



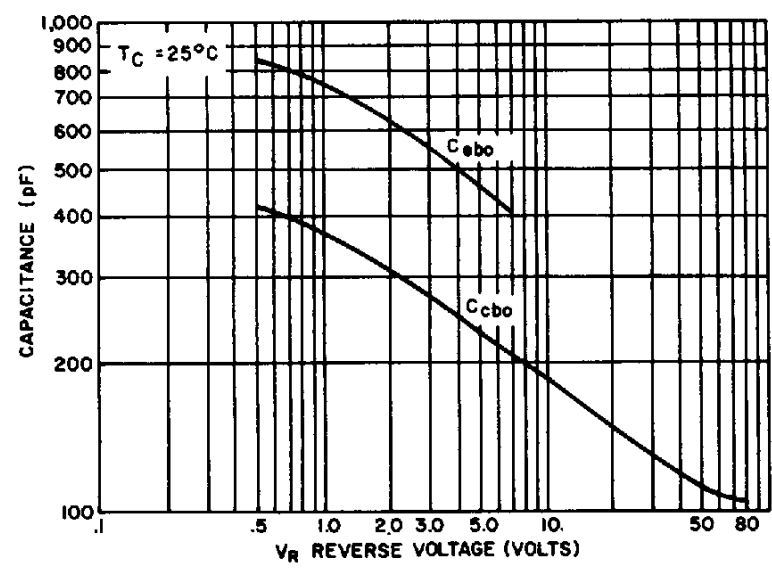
2. COLLECTOR SATURATION REGION



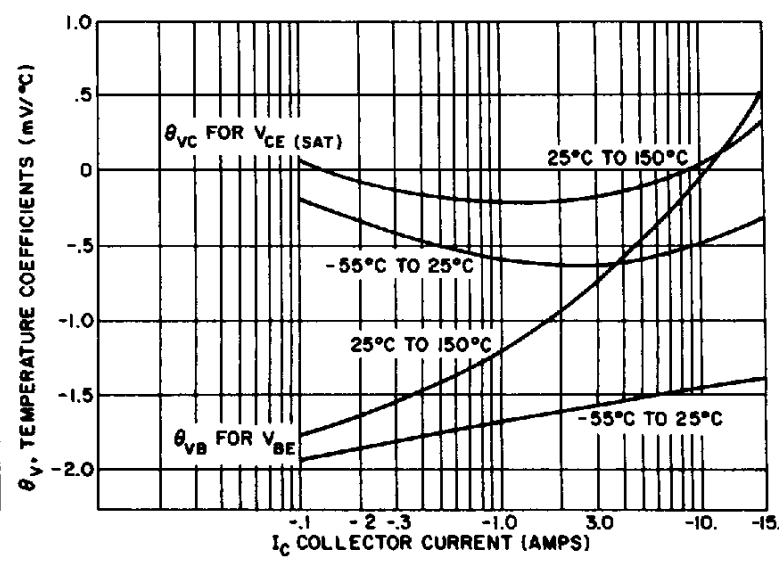
3. COLLECTOR CUTOFF REGION



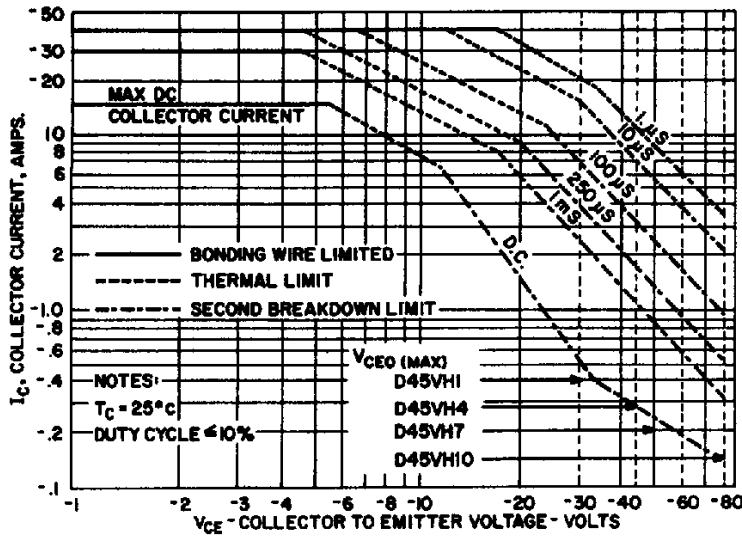
4. SATURATION VOLTAGE



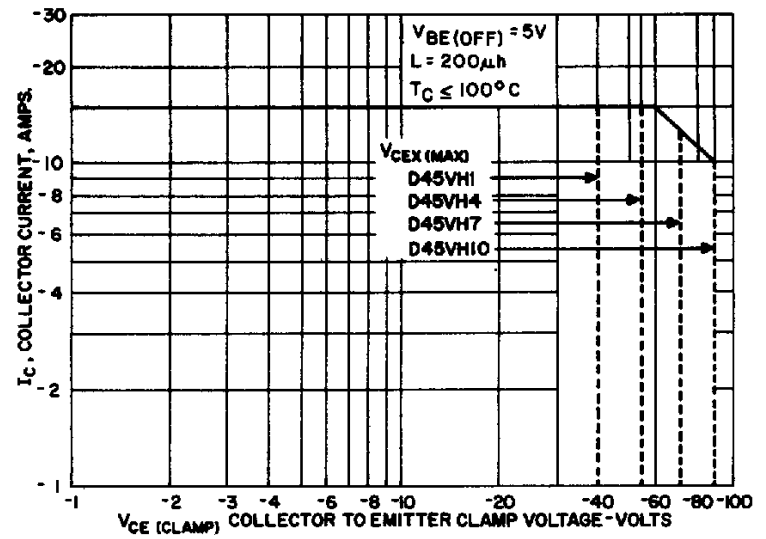
5. CAPACITANCE



6. SATURATION VOLTAGE TEMPERATURE COEFFICIENTS

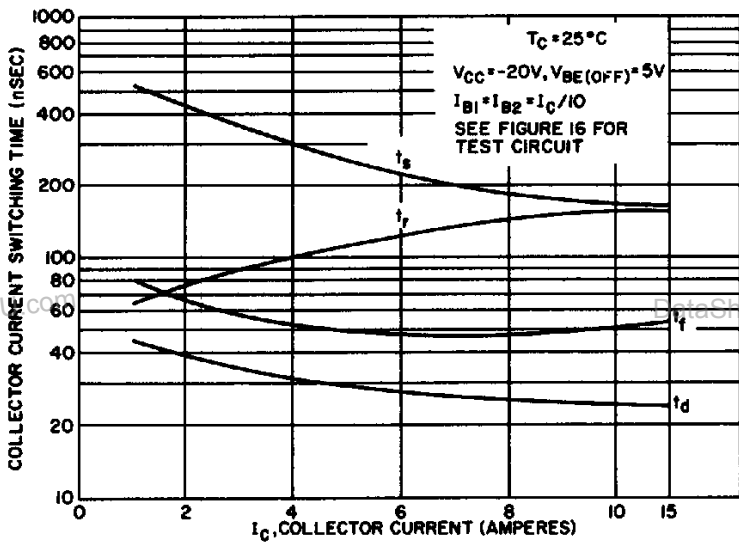


7. FORWARD BIAS SOA

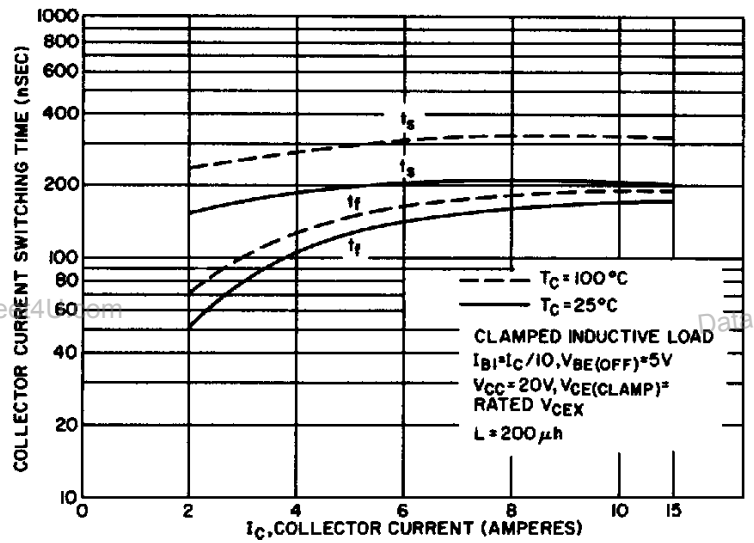


8. REVERSE BIAS SOA

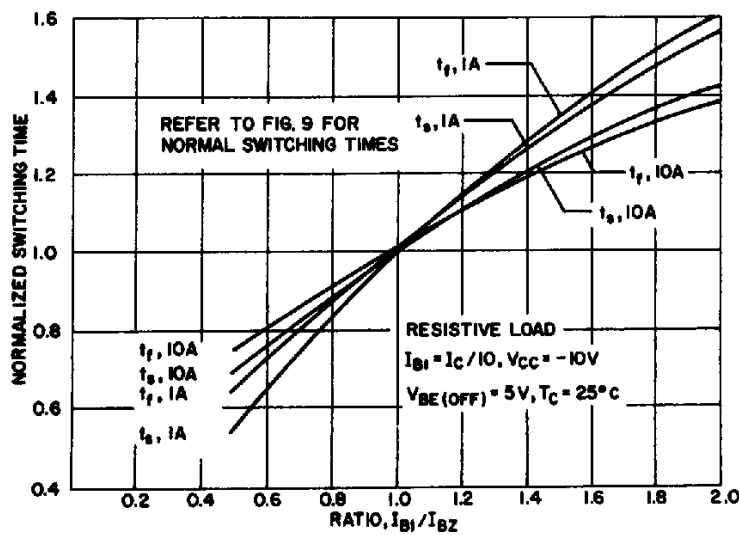
TYPICAL SWITCHING CHARACTERISTICS



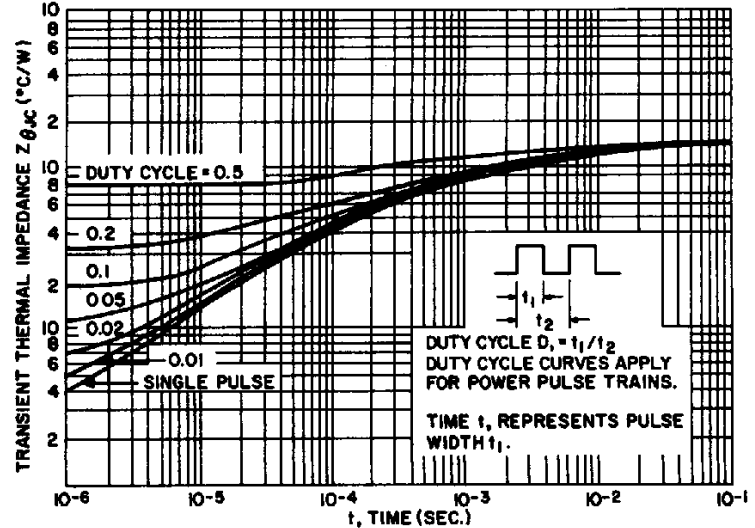
9. RESISTIVE SWITCHING TIME



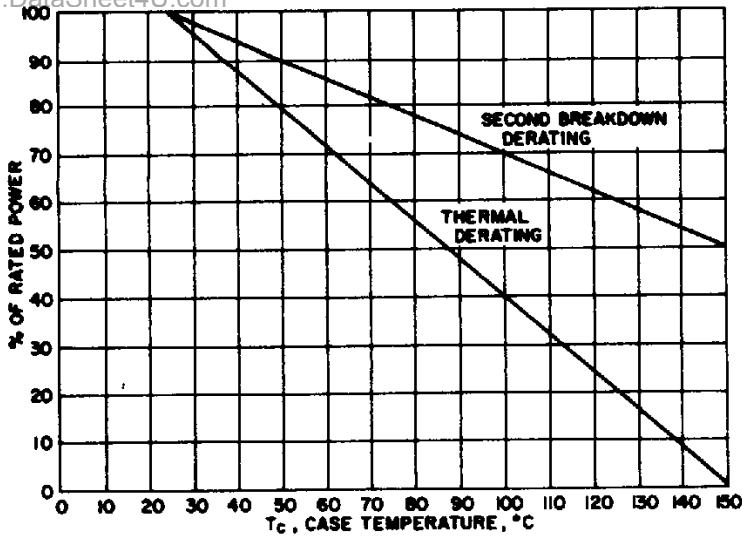
10. CLAMPED INDUCTIVE SWITCHING TIME



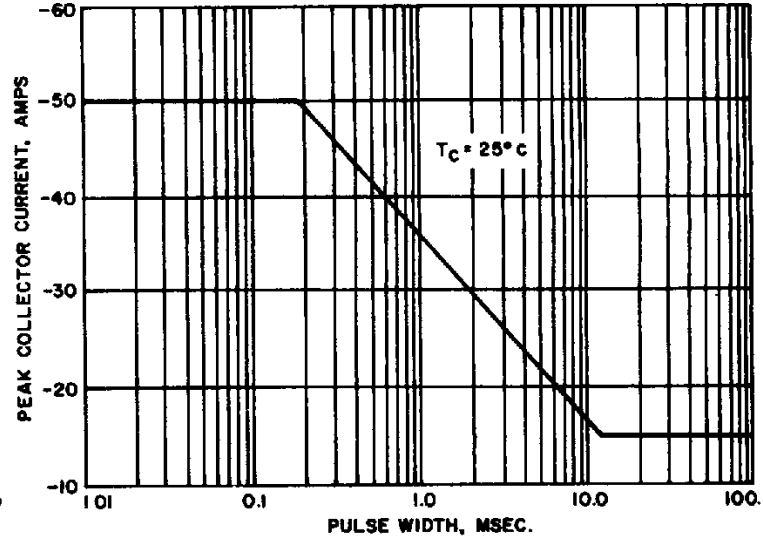
11. SWITCHING TIME VARIATION WITH I_{B2}



12. TRANSIENT THERMAL RESPONSE

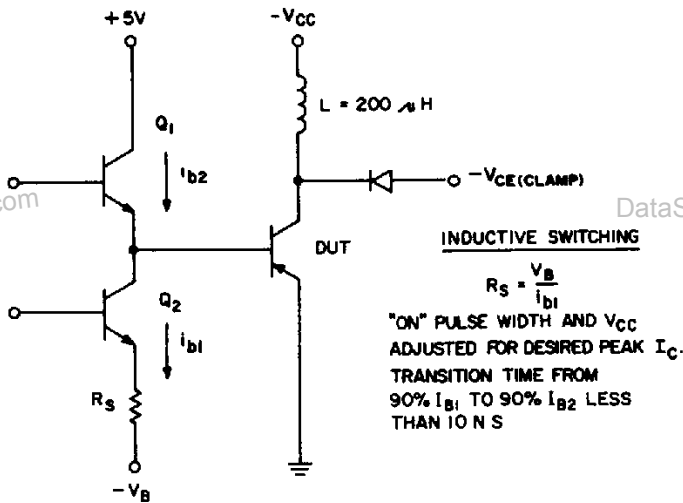


13. POWER DERATING FACTOR

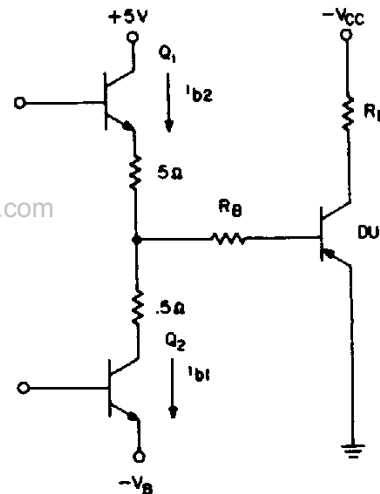


14. MAXIMUM SINGLE PULSE COLLECTOR CURRENT

TEST CIRCUITS



15. INDUCTIVE SWITCHING AND V_{CEX}



RESISTIVE SWITCHING

$$R_C = \frac{V_{CC}}{I_C}, \text{ NON-INDUCTIVE}$$

$$R_B = \frac{V_B}{I_{B1}} - 0.5$$

TRANSITION TIME 90% I_{B1} TO 90% I_{B2} LESS THAN 10 NS

16. RESISTIVE SWITCHING